



Attorney's Docket No.: 07977-182002 / US3413D1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2823  
Serial No. : 09/635,832 Examiner : Fernando Toledo  
Filed : August 9, 2000 Confirmation No.: 6795  
Title : SEMICONDUCTOR DEVICE HAVING SOI STRUCTURE AND  
MANUFACTURING METHOD THEREFOR

**MAIL STOP RCE**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

  
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Date: July 20, 2005

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-182002	Application No. 09/635,832
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant Shunpei Yamazaki et al.	
		Filing Date August 9, 2000	Group Art Unit 2823
(37 CFR §1.98(b))			

### U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,454,524	06/12/1984	Spence			03/06/1978
	AB	4,549,336	10/29/1985	Sheppard Douglas P.			05/09/1984
	AC	4,697,198	09/29/1987	Komori et al.			08/08/1985
	AD	5,196,367	03/23/1993	Lu et al.			05/08/1991
	AE	5,198,879	03/30/1993	Ohshima			03/19/1991
	AF	5,324,960	06/28/1994	Pfiester et al.			01/19/1993
	AG	5,343,051	08/30/1994	Yamaguchi et al.			05/10/1993
	AH	5,350,940	09/27/1994	Rona			12/06/1991
	AI	5,426,325	06/20/1995	Chang et al.			08/04/1993
	AJ	5,428,234	06/27/1995	Sumi			09/16/1994
	AK	5,449,937	09/12/1995	Arimura et al.			02/21/1995
	AL	5,532,175	07/02/1996	Racanelli et al.			04/17/1995
	AM	5,548,143	08/20/1996	Lee			12/05/1995
	AN	5,606,191	02/25/1997	Wang			04/14/1995
	AO	5,608,231	03/04/1997	Ugajin et al.			07/18/1996
	AP	5,614,752	03/25/1997	Takenaka			01/04/1994
	AQ	5,619,053	04/08/1997	Iwamatsu et al.			05/31/1995
	AR	5,635,749	06/03/1997	Hong			09/29/1995
	AS	5,661,059	08/26/1997	Liu et al.			04/18/1995
	AT	5,670,389	09/23/1997	Huang et al.			01/11/1996
	AU	5,674,788	10/07/1997	Wristers et al.			06/06/1995
	AV	5,675,164	10/07/1997	Brunner et al.			06/07/1995
	AW	5,698,884	12/16/1997	Dennen			02/07/1996
	AX	5,731,612	03/24/1998	Buxo et al.			04/28/1997
	AY	5,786,618	07/28/1998	Wen			03/21/1996
	AZ	5,801,416	09/01/1998	Choi et al.			01/24/1996
	AAA	5,831,294	11/03/1998	Ugajin			01/16/1997

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)		S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-182002	Application No. 09/635,832
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.		
		Filing Date August 9, 2000	Group Art Unit 2823	

<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ABB	5,885,872	03/23/1999	Tamaki et al.			12/20/1996
	ACC	5,893,740	04/13/1999	Chang et al.			01/27/1997
	ADD	5,894,151	04/13/1999	Yamazaki et al.			02/19/1993
	AEE	5,905,291	05/18/1999	Utsunomiya et al.			07/18/1995
	AFF	5,952,699	09/14/1999	Yamazaki et al.			08/19/1997
	AGG	6,107,654	08/22/2000	Yamazaki			02/08/1999
	AHH	6,111,296	08/29/2000	Yamazaki et al.			08/13/1997
	AII	6,118,148	09/12/2000	Yamazaki			11/04/1997
	AJJ	6,198,141 B1	03/06/2001	Yamazaki et al.			08/13/1997
	AKK	6,218,714 B1	04/17/2001	Yamazaki			08/08/1997
	ALL	6,251,733 B1	06/26/2001	Yamazaki			04/07/2000
	AMM	6,617,647 B2	09/09/2003	Yamazaki			03/16/2001
	ANN	6,653,687 B1	11/25/2003	Yamazaki			08/08/1997
	AOO	6,690,075 B2	02/10/2004	Yamazaki			06/04/2001
	APP	6,703,671 B1	03/09/2004	Yamazaki et al.			07/28/1999
	AQQ	6,867,085 B2	03/15/2005	Yamazaki et al.			12/13/2000

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes      No
	ARR	61-256769	11/14/1986	JAPAN			AB
	ASS	02-031464	02/01/1990	JAPAN			AB
	ATT	02-159070	06/19/1990	JAPAN			AB
	AUU	02-196468	08/03/1990	JAPAN			AB
	AVV	02-203566	08/13/1990	JAPAN			AB
	AWW	04-206971	07/28/1992	JAPAN			AB
	AXX	04-286339	10/12/1992	JAPAN			AB
	AYY	05-283687	10/29/1993	JAPAN			AB

Examiner Signature	Date Considered
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<b>Information Disclosure Statement</b> <b>by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))			
<b>JUL 20 2005</b>		Applicant Shunpei Yamazaki et al. Filing Date August 9, 2000	Group Art Unit 2823

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
	AZZ	06-244103	09/02/1994	JAPAN			AB
	AAAA	07-135318	05/23/1995	JAPAN			AB
	ABBB	07-321339	12/08/1995	JAPAN			AB
	ACCC	GB 2 316 227	11/21/2001	United Kingdom			In English

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>		
Examiner Initial	Desig. ID	Document
	ADDD	Kwok K. Ng; "Complete Guide to Semiconductor Devices"; pp. 164-165; Published by McGraw-Hill, Inc.; 1995

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